

**ELECTRONIC INFORMATION DISCLOSURE STATEMENT**

Electronic Version v18

Stylesheet Version v18.0

**Title of Invention****METHOD TO SELECTIVELY CORRECT CRITICAL DIMENSION ERRORS IN THE SEMICONDUCTOR INDUSTRY**

Application Number:

Confirmation Number:

First Named Applicant: Jed Rankin

Attorney Docket Number: BUR920040086US1

Search string: ( 6653231 or 6630288 or 5468595 or 20020160628 or 20020160320 ).pn.

**US Patent Documents****Note: Applicant is not required to submit a paper copy of cited US Patent Documents**

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	6653231	2003-11-25	Okoroanyanwu et al			
	2	6630288	2003-10-07	Shields et al			
	3	5468595	1995-11-21	Livesay			

**US Published Applications****Note: Applicant is not required to submit a paper copy of cited US Published Applications**

init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
	1	20020160628	2002-10-31	Okoroanyanwu et al			
	2	20020160320	2002-10-31	Shields et al			

**Signature****Examiner Name****Date**